FAMPAT

Comprehensive Worldwide Patent Family Database

Summary

FAMPAT

Comprehensive Worldwide Patent Family Database

Country coverage:

FamPat covers patent families in all disciplines. The documents are from:
- 95 national offices (list on page 3),
- 6 regional offices (EPO, WIPO, OAPI, ARIPO, EAPO, and CCG).
Utility models are also covered for 38 countries (list on page 3).

Contents:

- A single family record groups together all publication stages of the family members, from applications published to granted patents.
Questel has developed a family definition which incorporates the EPO's strict family rule with additional rules which take into account different patenting authorities' definitions of an invention, particularly for Japanese publications, links between parent EP and/or PCT applications and links between US Provisionals and US Published Applications.

- Official English language abstracts are provided for near half of families. This coverage is supplemented by abstracts in French, German, Spanish etc. English language machine translations of French, German, Japanese, Chinese, Korean and Taiwanese publications… are searchable and this machine-translated data is replaced by the official English data when available.

- For records containing WO, US, EP, AT, BE, BR, CA, CH, CN, DE, ES, FR, GB, IN, JP, KR, RU, TW, DK, FI, SE, and TH publications, the bibliography is completed with the full text of the description and claims of these publications (details on page 4).
In addition, for US, EP, WO, GB, and CA publications, the records are enhanced by information extracted from the full text and searchable in four fields – Patent Object (OBJ), Advantages of the invention and Disadvantages of the prior art (ADB), Independent Claims (ICLM) and Concepts (KEYW).

- The images are available for US publications from 1880, EP and WO publications from 1978, JP-Kokai from 1980, GB from 1920, FR from 1978, DE from 1980, CA from 1989, KR from 1979, CN from1985, TW from 2004, BR from 2009, IN from 2005 and RU from 1994. Partial coverage for CH, VN and IL.

- Legal status information for approximately 60 countries (see coverage on page 5)

- Also available :
- Classifications Codes: Cooperative Patent Classification (CPC), International Patent Classification (IPC), US (PCL), Japanese (FI and F-term) and old EPO Classifications (ECLA, ICO).
- Cited patents and non-patent literature from approximately 30 offices.

Date coverage:

From 1800 onwards. Start dates vary according to countries. List of dates available on page 3.

Number of records:
Near 53 million families

Updating:
Weekly

Language of records:
Multilingual

SDI profile:
Weekly or monthly
Update code details on page 43

Producer:
Questel http://www.questel.com

■ Bibliographic Information Coverage Details:

Year in parentheses indicates the year of earliest documents.

Country	Country Code	Coverage
Algeria (2000)	DZ	2002
Argentina*	AR	1973
ARIPO (African Regional Industrial Property Org.) (1971)	AP	1984
Australia	AU	1922
Austria*	AT	1899
Belarus	BY	1997
Belgium (1875)	BE	1926
Bosnia and Herzegovina	BA	1998
Brazil*	BR	1973
Bulgaria*	BG	1973
Canada	CA	1874
Chile*	CL	2005
China*	CN	1985
Colombia*	CO	1995
Costa Rica*	CR	2007
Croatia	HR	1994
Cuba	CU	1974
Cyprus (1921)	CY	1975
Czech Republic* (1985)	CZ	1993
Czechoslovakia (1951)	CS	1973-1993
Denmark*	DK	1895
Dominican Republic*	DO	2002
EAPO (Eurasian Patent Org.)	EA	1996
Ecuador*	EC	1990
Estonia*	EE	1995
Egypt	EG	1976
El Salvador (1970)	SV	2000
EPO (European Patents Office)	EP	1978
Finland* (1842)	FI	1968
France (1902)	FR	1920
GCC (Gulf Cooperation Council)	GC	2002
Georgia*	GE	2006
Germany* (1861)	DE	1879
Germany* (former DR)	DD	1952-1999
Greece* (1920)	GR	1977
Guatemala	GT	1966
Honduras*	HN	2005
Hong Kong	HK	1976
Hungary*	HU	1973
Iceland (1926)	IS	1993
India (1912)	IN	1975
Indonesia (1988)	ID	1996
Ireland (1930)	IE	1973
Israel	IL	1968
Italy* (1927)	IT	1973
Japan* (1928)	JP	1971
Jordan	JO	1971
Kazakhstan	KZ	1993
Kenya	KE	1975-1989
Korea (south)*	KR	1978
Kyrgyzstan	KG	2002

Country	Country Code	Coverage
Latvia	LV	1993
Lithuania	LT	1992
Luxembourg	LU	1945
Malawi	MW	1973-1994
Malaysia	MY	1953-1989 2003
Malta	MT	1968-1992
Mexico	MX	1980
Moldova*	MD	1994
Monaco (1957)	MC	1975
Mongolia	MN	1972-1989
Montenegro	ME	2010
Morocco	MA	1979
Netherlands (1856)	NL	1964
New Zealand	NZ	1978
Nicaragua	NI	2003
Norway (1909)	NO	1923
OAPI (Org. Africaine de la Propriété Industrielle)	OA	1992
Panama	PA	1996
Peru*	PE	1992
Philippines*	PH	1975-1999
Poland*	PL	1973
Portugal*	PT	1976
Romania	RO	1973
Russian Federation*	RU	1993
San Marino	SM	2000
Serbia (Republic of)*	RS	2006
Serbia and Montenegro*	YU	1996-2006
Singapore	SG	1983
Slovakia	SK	1993
Slovenia	SI	1992
South Africa (1968)	ZA	1971
Soviet Union (1928)	SU	1961
Spain* (1827)	ES	1930
Sweden	SE	1891
Switzerland (1888)	CH	1905
Tadjikistan*	TJ	1998
Taïwan* (1991)	TW	2000
Thailand	TH	1982
Trinidad & Tobago	TT	1994
Tunisia	TN	1990
Turkey*	TR	1973
Ukraine* (1987)	UA	1999
United Kingdom (1840)	GB	1893
United States	US	1836
Uruguay*	UY	2000
Uzbekistan	UZ	1997
Vietnam*	VN	1984-1997
WIPO (World Intellectual Property Org.)	WO	1978
Zambia	ZM	1968-1994
Zimbabwe	ZW	1980-1995

* Utility models are also covered.

Coverage details by type of publication (kind code) is available with this link:
https://www.questel.com/resources/coverage-updates/#anchor-0

■ Fulltext Coverage Details:

Country	Country Code	Original Language	English Machine Transl.	Coverage
WIPO (World Intellectual Property Organization)	WO	English or German or French or Spanish or Portuguese or Russian or Japanese or Korean or Chinese	✓	1978
EPO (European Patent Office)	EP	English or French or German (applications) English, French and German (granted)	✓	1978 (applications) 1980 (patents)
United States	US	English		1880 (patents) 2001 (applications)
Austria	AT	German		1902-2005 (patents – partial coverage from 1964 to 1990 and from 1996 to 1999 – years 51 to 58 and 91 to 95 not covered) 1994-2005 (utility models – partial coverage until 1999) 2005 (applications – partial coverage)
Belgium	BE	Dutch or French or German		1925 (partial coverage until 1963, yeard 71-82 not covered)
Brazil	BR	Portuguese	✓	1982 (partiel coverage from 1982 to 2000 and from 2006 – years 2001 to 2005 not covered)
Canada	CA	English or French/English		1978-1989 (old law) 1989 (new law)
China	CN	Chinese	✓	1985 (unexamined applications) 1985-1992 (examined applications) 1993 (patents) 1985 (utility models)
Denmark	DK	Danish	✓	1993 (patents)
Finland	FI	Finnish	✓	1997 (patents)
France	FR	French	✓	1920 (applications)
Germany	DE	German	✓	1976 (applications) 1976 (patents) 1976 (utility models)
India	IN	English		2005 (applications and patents)
Japan	JP	Japanese	✓	1993 (applications and utiity models) 1996 (patents)
Korea (south)	KR	Korean	✓	2000 (applications) 2008 (utility models)
Russia	RU	Russian	✓	1924-1993 (Soviet publications) 1993 (patents) 1994 (utility models) 2009 (applications)
Spain	ES	Spanish	✓	1980-1992 (patents) 1993 (applications) 1980 (utility models)
Sweden	SE	Swedish	✓	1994 (patents)
Switzerland	CH	German or French or Italian		1920 (patents – partial coverage until 1997)
Taïwan	TW	Chinese	✓	2003 (applications) 2004 (patents and utility models)
Thailand (claims only) *Partial coverage*	TH	Thaï	✓	1980 (applications) 1984 (patents)
United Kingdom	GB	English		1920 (applications)

■ Legal Status Coverage Details:

Information come from the European Patent Office “Legal status” database also known as PRS (Patent Register Service) which covers events occuring during the patent cycle and may affect the legal status of published applications or granted patents. Approximately sixty patent authorities are covered.

Country	Country Code	Coverage
WIPO	WO	1978
EPO	EP	1978
EAPO	EA	1998
United States	US	1980
Argentina	AR	2004
Australia	AU	2000
Austria	AT	1970
Belgium	BE	1984
Brazil	BR	1995
Canada	CA	1979
China	CN	1985
Colombia	CO	2003
Costa Rica	CR	1980
Cuba	CU	2009
Czech Rep.	CZ	2000
Denmark	DK	1983
El Salvador	SV	1971
Estonia	EE	2003
Finland	FI	1993
France	FR	1969
Germany	DE	1971
Germany (former East)	DD	1992-2004
Greece	GR	2002
Hong Kong	HK	2004
Hungary	HU	1990
Ireland	IE	1993
Israel	IL	1996
Italy	IT	1990
Japan	JP	2004
Korea (South)	KR	1992
Lithuania	LT	1995
Mexico	MX	2005
Moldova (Rep. of)	MD	2006
Monaco	MC	1972-1992
Netherlands	NL	1973
New Zealand	NZ	2001
Norway	NO	2001
Peru	PE	2007
Philippines	PH	1990
Poland	PO	2007
Portugal	PT	1991
Russia	RU	2005
Slovenia	SI	2004
Spain	ES	1992
Sweden	SE	1995
Switzerland	CH	1971
Taiwan	TW	2000
United Kingdom	GB	1969

For ARIPO, Bulgaria, Belize, Belarus, Croatia, Egypt, Georgia, Kenya, Latvia, Malaysia, Romania, Slovakia, South Africa, Thailand, United Arab Emirates and Uzbekistan, the database only contains information on entry into national phase of the corresponding PCT application or validity of the EP.
For Luxembourg, the database only covers the Supplementary Protection Certificates.

Sample Records

MAXL IMG Format

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  1/1 FAMPAT - (C) Questel- image
  CPIM Questel
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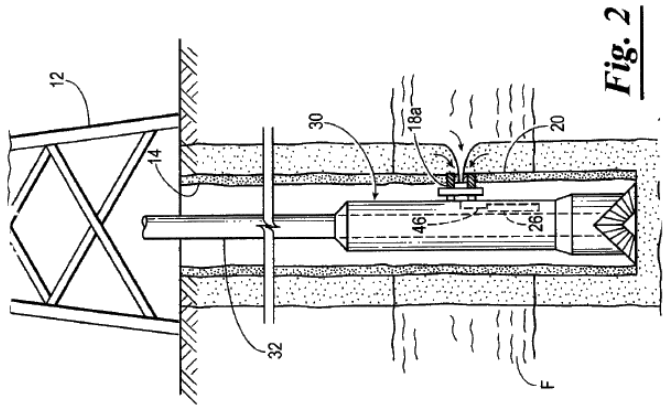

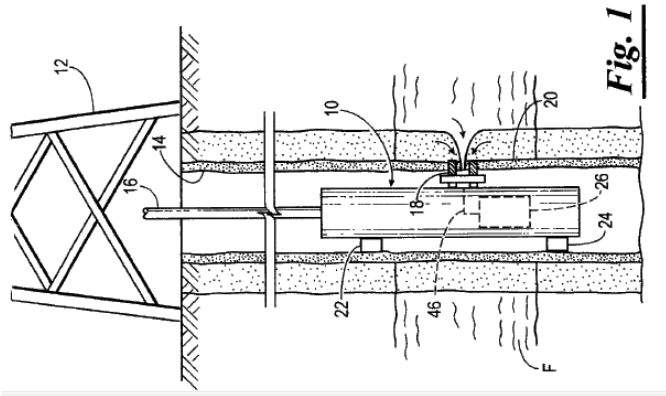


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  FAN - 4095714
  PN  - GB0608349           D0 2006-06-07 [GB200608349]
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            AP : 2006GB-0008349 2006-04-27
      - CA2544866           A1 2006-10-29 [CA2544866]
            STG: (A1) Application laid open
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      - NO20061817          A  2006-10-30 [NO200601817]
            STG: (A) Published application
            AP : 2006NO-0001817 2006-04-25
      - US2006243033        A1 2006-11-02 [US20060243033]
            STG: (A1) Application published
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      - US2006243047        A1 2006-11-02 [US20060243047]
            STG: (A1) Application published
            AP : 2005US-11203932 2005-08-15
      - DE102006019813      A1 2006-11-02 [DE102006019813]
            STG: (A1) Doc. laid open (First publication)
            AP : 2006DE-10019813 2006-04-28
      - FR2885166           A1 2006-11-03 [<B>FR2885166</B]
            STG: (A1) Application for patent of invention, (first publ.)
            AP : 2006FR-0003697 2006-04-21
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      - GB2425794           A  2006-11-08 [GB2425794]
            STG: (A) Published Application
            AP : 2006GB-0008349 2006-04-27
      - WO2006117604        A1 2006-11-09 [WO2006117604]
            STG: (A1) Published application with search report
            AP : 2006WO-IB00919 2006-04-19
      - CA2605830           A1 2006-11-09 [CA2605830]
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            AP : 2006CA-2605830 2006-04-19
      - CN1912341           A  2007-02-14 [CN1912341]
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            AP : 2006CN-0089814 2006-04-29
      - MXPA06004693        A  2007-04-24 [MX2006PA004693]
            STG: (A) Patent application
            AP : 2006MX-PA04693 2006-04-27
      - GB2425794           B  2007-07-04 [GB2425794]
            STG: (B) Patent specification
            AP : 2006GB-0008349 2006-04-27
      - RU2006114647        A  2007-11-20 [RU2006114647]
            STG: (A) Application for invention
            AP : 2006RU-0114647 2006-04-28
      - NO20075593          A  2007-11-23 [NO200705593]
            STG: (A) Published application
            AP : 2007NO-0005593 2007-11-05
      - EP1877646           A1 2008-01-16 [EP1877646]
            STG: (A1) Application published with search report
            AP : 2006EP-0744517 2006-04-19
      - MX2007013221        A  2008-01-16 [MX2007013221]
            STG: (A) Patent application
            AP : 2007MX-PA13221 2007-10-23
      - CN101189409         A  2008-05-28 [CN101189409]
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            AP : 2006CN-80019958 2006-04-19
      - US7458252           B2 2008-12-02 [US7458252]
            STG: (B2) Granted patent as second publication
            AP : 2005US-10908161 2005-04-29
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      - US7461547           B2 2008-12-09 [US7461547]
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            FD : Previous publication: US20060243047 A1 2006-11-02 [
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      - RU2007144207        A  2009-06-10 [RU2007144207]
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            AP : 2007RU-0144207 2006-04-19
      - EP1877646           B1 2009-06-24 [EP1877646]
            STG: (B1) Patent specification
            AP : 2006EP-0744517 2006-04-19
      - DE602006007458      D1 2009-08-06 [DE602006007458]
            STG: (D1) Grant (no unexamined application published) patent law 81
            AP : 2006DE-60007458 2006-04-19
      - CA2544866           C  2009-10-20 [CA2544866]
            STG: (C) Patent (second level)
            AP : 2006CA-2544866 2006-04-25
      - RU2391503           C2 2010-06-10 [RU2391503]
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            AP : 2006RU-0114647 2006-04-28
      - RU2392430           C2 2010-06-20 [RU2392430]
            STG: (C2) Patent for invention ( 2nd publ.)
            AP : 2007RU-0144207 2006-04-19
      - CN101189409         B  2012-01-11 [CN101189409B]
            STG: (B) Granted patent for invention
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      - CA2605830           C  2014-05-27 [CA2605830]
            STG: (C) Patent (second level)
            AP : 2006CA-2605830 2006-04-19
  TI  - Methods and apparatus of downhole fluid analysis
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        Schlumberger Technology B.V. [NL]; Services Petroliers Schlumberger
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        HOLDINGS LIMITED [VG];
  PAH - (US7461547)
        TERABAYASHI TORU; CHIKENJI AKIHITO; YAMATE TSUTOMU; MULLINS OLIVER C;
        KURKJIAN ANDREW L; ELSHAHAWI HANI
      - Schlumberger Technology Corporation, Sugar Land TX [US];
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        SCHLUMBERGER TECHNOLOGY CORPORATION; 110 Schlumberger Drive, Sugar
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        Toru [JP]; CHIKENJI, Akihito [FR]; YAMATE, Tsutomu [JP]; MULLINS,
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        BROWN, JONATHAN W. [ZZ]; KURKJIAN, ANDREW L. [ZZ]; DONG, CHENGLI [ZZ];
        DHRUVA, BRINDESH [ZZ]; HAVLINEK, KENNETH L. [ZZ]; GOODWIN, ANTHONY R.
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  PAH - (CA2605830)
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      - SCHLUMBERGER CANADA LIMITED [CA]; TERABAYASHI, TORU [ZZ]; CHIKENJI,
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  REAS- TERABAYASHI T; FROM 2005-08-15 TO 2005-08-18
      - YAMATE T; FROM 2005-08-15 TO 2005-08-18
      - MULLINS O; FROM 2005-08-15 TO 2005-08-19
      - EISHAHAWI H; FROM 2005-08-15 TO 2005-08-20
      - CHIKENJI A; FROM 2005-08-15 TO 2005-08-24
      - KURKJIAN A; FROM 2005-08-15 TO 2005-09-28
      - SCHLUMBERGER TECHNOLOGY; FROM 2005-08-18
  RPH - (EP1877646)
        Stoole, Brian David ; Sensa  [GB]
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      - Stoole, Brian David, et al [GB]
  RPH - (US7461547)
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        SCHLUMBERGER OILFIELD SERVICES [US]
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        2006-04-19
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  EC  - E21B-049/10 E21B-049/10; G01N-009/36; S01N-011/00S
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        MX MZ NA NG NI NO NZ OM PG PH PL PT RO RU SC SD SE SG SK SL SM SY TJ
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      - ARIPO:  BW GH GM KE LS MW MZ NA SD SL SZ TZ UG ZM ZW
      - EAPO:  AM AZ BY KG KZ MD RU TJ TM
      - EPO:  AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HU IE IS IT LT LU LV
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      - OAPI:  BF BJ CF CG CI CM GA GN GQ GW ML MR NE SN TD TG
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  CT  - (EP1877646)
        International Search Report [Examiner]
        -US5549159 (A) (Cat. X) [US5549159] SHWE THAN, et al
        -US5622223 (A) (Cat. X) [US5622223] VASQUEZ RAFAEL B
        -US2002194907 (A1) (Cat. X,D) [US20020194907] BOSTROM NEIL, et al
        -US5233866 (A) (Cat. A) [US5233866] DESBRANDES ROBERT
        -US2002112854 (A1) (Cat. A) [US20020112854] KRUEGER VOLKER, et al
        -US6128949 (A) (Cat. A) [US6128949] KLEINBERG ROBERT L
  CT  - (US7461547)
        Search Report [Examiner]
        -US4860581 (A) [US4860581] ZIMMERMAN THOMAS H, et al
        -US4936139 (A) [US4936139] ZIMMERMAN THOMAS H, et al
        -US6102673 (A) [US6102673] MOTT KEITH C, et al
        -US6148912 (A) [US6148912] WARD CHRISTOPHER D
        -US6189612 (B1) [US6189612] WARD CHRISTOPHER D
        -US6230824 (B1) [US6230824] PETERMAN CHARLES P, et al
        -US6296056 (B1) [US6296056] WARD CHRISTOPHER D
        -US6325159 (B1) [US6325159] PETERMAN CHARLES P, et al
        -US6467544 (B1) [US6467544] BROWN JONATHAN, et al
        -US6659177 (B2) [US6659177] BOLZE VICTOR M, et al
        -US6688390 (B2) [US6688390] BOLZE VICTOR M, et al
        -US6755086 (B2) [US6755086] SALAMITOU PHILIPPE F, et al
        -US6775996 (B2) [US6775996] COWANS KENNETH W
        -US7178591 (B2) [US7178591] DEL CAMPO CHRISTOPHER S, et al
      - Applicant citations
        -US3780575 (A) [US3780575] URBANOSKY H
        -US3859851 (A) [US3859851] URBANOSKY HAROLD J
        -US3954006 (A) [US3954006] ANDERSON RONALD A, et al
        -US4782695 (A) [US4782695] GLOTIN BERNARD J P, et al
        -US4994671 (A) [US4994671] SAFINYA KAMBIZ A, et al
        -US5167149 (A) [US5167149] MULLINS OLIVER C, et al
        -US5201220 (A) [US5201220] MULLINS OLIVER C, et al
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        -US5266800 (A) [US5266800] MULLINS OLIVER C
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AB - (EP1877646)
Methods and apparatus for downhole analysis of formation fluids by isolating the fluids from the formation and/or borehole in a pressure and volume control unit that is integrated with a flowline of a fluid analysis module and determining fluid characteristics of the isolated fluids. Parameters of interest may be derived for formation fluids in a static state and undesirable formation fluids may be drained and replaced with formation fluids that are suitable for downhole characterization or surface sample extraction. Isolated formation fluids may be circulated in a loop of the flowline for phase behavior characterization. Real-time analysis of the fluids may be performed at or near downhole conditions.
- (From US2006243047 A1)
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        Exemplary Claim Number: ECL=1
        Independent Claim Number: ICL=26
        Primary examiner: Frank, Rodney T
        Assistant examiner: Frank Rodney T
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        Number of Drawings: NDR=8
        Number of Figures: NFG=0
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        Extended under 35 USC 154(b) the following days: EXTD=104
        Primary examiner: Frank, Rodney T
        Assistant examiner: Frank Rodney T
  NO  - (WO2006117604)
        Extended kind: x
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        [0014] In at least one aspect, the present invention relates to a
        fluid analysis assembly for analyzing a fluid.
      - [0019] In another aspect, the present invention relates to a down hole
        tool positionable in a well bore having a wall and penetrating a
        subterranean formation.
      - [0021] The present invention also relates to a method for measuring a
        parameter of an unknown fluid within a well bore penetrating a
        formation having the fluid therein.
  ADB - (US20060243033)
        [0013] It is, therefore, desirable to provide techniques capable of
        performing formation evaluation of fluid that is representative of
        fluid in the formation. It is further desirable that such techniques
        provide accurate and real-time measurements.
      - This permits comparisons of the results of the samples to provide a
        better indication of the accuracy of the down hole measurements.
      - This permits comparisons of the results of the samples to provide a
        better indication of the accuracy of the down hole measurements.
      - Such loop mixing may also be desirable in other applications that do
        not involve narrow flowlines.
  ICLM- (US20060243033)
        1. A fluid analysis assembly for analyzing a fluid, the fluid analysis
        assembly comprising: a chamber defining an evaluation cavity for
        receiving the fluid; a fluid movement device having a force medium
        applying force to the fluid to cause the fluid to move within the
        cavity; a pressurization assembly changing the pressure of the fluid
        in a continuous manner; and at least one sensor communicating with the
        fluid for sensing at least one parameter of the fluid while the
        pressure of the fluid is changing in the continuous manner.
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- 9. A down hole tool positionable in a well bore having a wall and penetrating a subterranean formation, the formation having a fluid therein, the down hole tool comprising: a housing; a fluid communication device extendable from the housing for sealing engagement with the wall of the well bore, the fluid communication device having at least one inlet for receiving the fluid from the formation; a fluid analysis assembly positioned within the housing for analyzing the fluid, the fluid analysis assembly comprising: a chamber defining an evaluation cavity for receiving the fluid from the fluid communication device; a fluid movement device having a force medium applying force to the fluid to cause the fluid to move within the evaluation cavity; a pressurization assembly changing the pressure of the fluid; and at least one sensor communicating with the fluid for sensing at least one parameter of the fluid.
- 21. A method for measuring a parameter of an unknown fluid within a well bore penetrating a formation having the fluid therein, comprising the steps of: positioning a fluid communication device of the down hole tool in sealing engagement with a wall of the well bore; drawing fluid out of the formation and into an evaluation cavity within the down hole tool; moving the fluid within the evaluation cavity; and sampling data of the fluid while the fluid is being moved within the evaluation cavity.
- 27. A down hole tool positionable in a well bore having a wall and penetrating a subterranean formation, the formation having a fluid therein, the down hole tool comprising: a housing; a fluid communication device extendable from the housing for sealing engagement with the wall of the well bore, the fluid communication device having at least one inlet for receiving the fluid from the formation; a fluid analysis assembly positioned within the housing for analyzing the fluid, the fluid analysis assembly comprising: a chamber defining an evaluation cavity configured as a re-circulating loop for receiving the fluid from the fluid communication device; a fluid movement device having a force medium applying force to the fluid to cause the fluid to re-circulate within the re-circulating loop; a pressurization assembly changing the pressure of the fluid; and at least one sensor communicating with the fluid for sensing at least one parameter of the fluid.

LEGL Format

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Basic Index (BI) + Super-Abstract index (SA)	/BI/SA (default)	If no field is specified, the search is conducted by default in the following fields: • English title-all stages of publication (ETIH) • French title-all stages of publication (FTIH) • German title-all stages of publication (GTIH) • Title in another language-all stages of publication (OTIH) • English abstract (EAB) • French abstract (FAB) • German abstract (GAB) • Abstract in another language (OAB) • English Index Words-FR publications only (IW) • Technology domain (TECD) • Drug name-French publications only (MED) • Object of the patent (OBJ) • Advantages and drawbacks of the invention over prior art (ADB) • Independent claims (ICLM) Search by : - Single terms using operators - Phrases using implied adjacency Truncation may be used. Left-hand truncation is available.	SPEECH RECOGNIZER? AND FREELY PIVOT+
Basic Index (Titles and Abstracts)	/BI	/BI restricts the search to the ETIH, FTIH, GTIH, OTIH, EAB, FAB, GAB, OAB, plus the IW, TECD and MED fields.	(MEMORY MANAGEMENT AND SPEECH ???RECOGNIZER?) /BI
Super-Abstract index (Key Content)	/SA	/SA restricts the search to 3 fields: OBJ, ADB and ICLM.	(PORTABLE AND MEASUR+ AND FLEXIB+ AND ACCELER+ AND FREELY PIVOT+) /SA

Details for fields in the BI and SA on next pages.

Basic Index (/BI) Details

Search by	Index	Search Hints	Examples
Title in English: Original, or official translation from the EPO or machine translation by Questel	/ETIH	English language machine translations are included for the following publications, and are replaced with the official English translations when available: WO, EP, BR, CN, DE, DK, ES, FI, FR, JP, KR, RU, SE, TH and TW. Search with single terms using Boolean or proximity operators and/or phrases using implied adjacency. Truncation may be used and left- hand truncation is available.	(MEMORY AND SPEECH??) /ETIH
	/ETI	Restricts the search to English titles in the most recent publication stage.	
Original title in French	/FTIH	The French language title is available for the following patent authorities: EP, FR, WO, CA, BE, CH. Search in French with single terms using Boolean or proximity operators and/or phrases using implied adjacency. Truncation may be used and left-hand truncation is available.	(PALIER 1W ROULEMENT?) /FTIH
	/FTI	Restricts the search to French titles in the most recent publication stage.	
Original title in German	/GTIH	The German language title is available for the following patent authorities: DE, EP, AT, CH, WO, DD. Search in German with single terms using Boolean or proximity operators and/or phrases using implied adjacency. Truncation may be used and left-hand truncation is available.	WALZLAGER? /GTIH
	/GTI	Restricts the search to German titles in the most recent publication stage.	
Original title in other languages	/OTIH	OTIH and OTI contain original titles published in a language other than English, French, or German. Non-Latin languages are displayable only on QWEB 3 and Orbit.	
/TI simultaneously searches the ETIH, FTIH, GTIH and OTIH fields. The title displayed in the TI field is from the most recent publication stage in the preferred language.			
English Index Words	/IW	For French patent documents from 1987 through 2009. Search with single terms using operators or by phrases using implied adjacency. With the IND and MEMS commands, use the /IT index.	STACK SUPPORT /IW +LOADING /IW

Basic Index (/BI) Details (cont'd)

Search by	Index	Search Hints	Examples
English abstract: Original, or official translation from the EPO or machine translation by Questel	/EAB	If there is no official English abstract available, the EAB field will contain the English abstract of a family member if possible, or machine translated abstracts from the following authorities: WO, EP, BR, CN, DE, DK, ES, FI, FR, JP, KR, RU, SE, TH and TW, to be replaced by the official version when available. Search in English with single terms using operators and/or phrases using implied adjacency. Truncation may be used.	(TIME W INDEX) /EAB (PHENYL AND +VIRAL) /EAB
Original abstract in French	/FAB	French abstracts are provided primarily for WO, EP, FR, CA and BE publications from 1978 on. Search in French with single terms using operators and/or phrases using implied adjacency. Truncation may be used.	(COLLECTEUR SOLAIRE PLAT AND CHAMBRE? AND (SOUS W VIDE)) /FAB
Original abstract in German	/GAB	German abstracts are provided for DE publications from 1989, EP from 1978 and WO from 1995. Search in German with single terms using operators and/or phrases using implied adjacency. Truncation may be used.	BELEUCHTUNGSEINRICHTUNG /GAB
Original abstract in other languages	/OAB	Abstracts published in other languages such as: - Russian (SU, RU) - Japanese (JP) - Chinese (CN, TW) - Korean (KR) - Spanish (ES, MX, AR, CR, PA, PE, NI, SV, UY, GT, CO, EC, CU, CL, DO, WO) - Portuguese (BR, PT) - Italian (IT) - Turkish (TR) - Hungarian (HU) Mainly available from 1984. Especially useful for the display of records Non-Latin languages are displayable only on QWEB 3 and Orbit.	
/AB simultaneously searches the EAB, FAB GAB and OAB fields. The abstract displayed in AB is one that meets the preferred language.			
Technology Domain 35 areas listed on last page	/TECD	Questel indexing based on class titles or subclasses of the IPCs. Search with single terms using operators and/or phrases using implied adjacency. Truncation may be used. With the IND and MEMS commands, use the /TECT index.	OPTICS /TECD (MACHINE TOOL?) /TECD IND /TECT
Drug name with French SPC (extension of a patent EP or FR) Not provided after September 2009	/MED	Search with single terms using operators and/or phrases using implied adjacency. Truncation may be used.	RIVAROXABAN /MED

Super-Indexes

Search by	Index	Search Hints	Examples
All abstracts	/ABS	Using the /ABS index searches all abstract fields simultaneously: EAB, FAB, GAB, OAB and IW.	(+PHENYL AND VIRAL+) /ABS
All titles and abstracts	/NOMT	Using the /NOMT index searches all title and abstract fields simultaneously: ETIH, FTIH, GTIH, OTIH, EAB, FAB, GAB, OAB and IW.	(+PHENYL AND VIRAL+) /NOMT

Super-Abstracts Index (/SA) Details

Search by	Index	Search Hints	Examples
Object of invention	/OBJ	Extracted from the fulltext of the: 1 - Following original English language publications: - EP published applications from 1988 (Euro-PCTs excluded)* - PCT published applications from mid 2001* - US granted patents from 1971 to 2000 - US published applications from 03/15/2001 - GB published applications from 1971 - CA published applications from 1911 * *Can find older documents, back to 1980 for EP and back to 2000 for WO.* 2 – Following English machine translated publications: - PCT published applications (except those published in Korean) - FR published applications from 1974 for single FR in families, from June 2015 for the other FR - CN published applications (patents and utility models) from 1985 Search in English with single terms using operators or with phrases using implied adjacency. Use truncation.	(PORTABLE AND MEASUR+ AND FLEXIB+ AND CLUB HEAD) /OBJ
Advantages of the invention & Drawbacks over prior art	/ADB		(ELECTRONIC? AND ACCELER+) /ADB
Independent claims: Including main or first claim	/ICLM		(FREELY PIVOT+) /ICLM

Claims and Description

Coverage details on page 4

Search by	Index	Search Hints	Examples
Claims in: - English - French - German - Other languages	/ECLM /FCLM /GCLM /OCLM	Search by: - Simple words using operators - Phrases using implied adjacency Use truncation. Left-hand truncation is available. Non-Latin languages in OCLM and ODES are displayable only on QWEB 3 and Orbit.	(PORTABLE AND MEASUR+ AND FLEXIB+ AND CLUB HEAD) /ECLM
Description in: - English - Other languages	/DESC /ODES		(ELECTRONIC? AND ACCELER+) /DESC
Examples included in the description of US publications from end of April 2005	/DESX		((OVABULMIN OR OVA) AND ENCAPSULAT+) /DESX
All claims	/CLMS	/CLMS simultaneously searches the ECLM, FCLM, GCLM and OCLM fields.	((COLLAPS+ OR PLIANT OR PLIABLE) AND (CLAVIER OR KEYBOARD)) /CLMS
All Claims and Descriptions	/TX	/TX simultaneously searches the ECLM, FCLM, GCLM, OCLM, ODES, DESC and DESX fields.	(FREELY PIVOT+) /TX

Concepts

Key concepts are extracted from the full text of the patent publications using linguistic technology and reflect the semantic content of the publications. The different concepts are classified in the field by decreasing score. The following publications are used to extract the concepts and also reflect the patenting authorities for in which the field is searched:
1 - Original English language publications:
- EP published applications from 1988 (Euro-PCTs excluded) (some older documents back to 1980)
- PCT published applications from mid 2001 (some older documents back to 2000)
- US granted patents from 1971 to 2000
- US published applications from 03/15/2001
- GB published applications from 1971
- CA published applications from 1911

2 - English machine translated publications:
- PCT published applications (except those published in Korean)
- FR published applications from 1969 for single FR in families, from June 2015 for the other FR
- CN published applications (patents and utility models) from 1985

Search by	Index	Search Hints	Examples
Concepts	/KEYW	Search by single terms using operators, or by phrases using implied adjacency. Use truncation. Left-hand truncation is available. With the IND and MEMS commands, use the /KEYC index.	(DRUM GRANULATOR) /KEYW IND /KEYC FERTILIZER
The figures that appear in parentheses after each concept represent the score of the concept and its number of occurrences. They are not searchable.			

Publication Data

Search by	Index	Search Hints	Examples
Publication data in the family: - Number	/PN	All the patent publication stages are searched with /PN. • Search using the patent/publication number in the following formats:	
		- If patent authority uses a continuous series: CCNNNNNNN If the number is <7 digits, infill with hyphen(s) after the country code to achieve the necessary number of characters.	EP-980063 /PN GB---9557 /PN
		- If the patent authority restarts its number series each year: Before 2000: CCYYNNNNN (if number is <5 digit, fill with zeros after the series year CCYY) After 2000: CCYYYYNNNNN CCYYYYNNNNNNN	WO9916958 /PN WO8909788 /PN WO200016958 /PN JP2000077507 /PN
- Country		• Search for publications by ISO country code	EP /PN
- Kind code		• Search by kind code. Truncation may be used.	B2 /PN B# /PN
- Date		• Search by publication date without numeric operators: YYYYMMDD YYYYMM YYYY	2000-02-16 /PN 2000-02 /PN 2000 /PN
		• To combine publication country and date, use the S operator.	(EP S 2005) /PN
Kind code and patent authority	/IKD	Search in the format CCKK. CC = country code KK = kind code Truncation ? or # may be used. This index can be used with the IND, MEM and MEMS commands.	EPA? /IKD EPB# /IKD

Publication Data (cont'd)

Search by	Index	Search Hints	Examples
Original PCT publication number	/PPN	Search with: • Questel standardized format: Before 2000: CCYYNNNNN After 2000: CCYYYYNNNNN • Publication date without numeric operators • Presence of the field	WO9838673 /PPN WO200353458 /PPN 1998-11 /PPN PPN=YES
Publication dates of all members (except OPD): - All publication dates - First publication date - Last publication date	/PD /PDF /PDL	Search in the format: YYYY-MM-DD YYYY-MM YYYY Use numeric operators: =, <, >, <=, >=	PD=2000-02-16 PDF<=1997-06 PDL>=1995 PD=1997-04-01:1997-05-15
Application publication date for each member	/PDA		PDA=2008-10-02 PDA<=1999-10 PDA>2007
Granted patent date: - Each member - The first in the family - The latest in the family	/PDG /EPDG /LPDG		PDG=1998-06-02 EPDG<=1998-06 LPDG>1998
Publication date of the first member (regardless of stage)	/EPD		EPD=2005-09-02 EPD<=2005-09 EPD>=2005
Other publication dates: - Effective date - Date of previous issue - Date of national stage U.S.C. 371	/OPD		OPD=2006-01-12 OPD<=2006-01 OPD>2006 OPD=2006-01:2007-01
Publication stage	/STG	Search by term for the type of publication. Note: This field is not standardized. It is recommended to use the Kind Code (see /IKD previous page).	(PATENT OR GRANTED) /STG
First publication country for the family	/EPNC	Search by country codes.	FR /EPNC (JP OR CN OR TW) /EPNC
Number of published members in a family	/NPN	Use numeric operators: =, <, >, <=, >=	NPN=1 NPN>=5 NPN=10:15

Application Data

Search by	Index	Search Hints	Examples
Family Application Data: - Number	/AP	Search using: • The application number in the format YYYYCC-NNNNNNN YYYY = 4-digit application year CC = ISO country code NNNNNNN= 7 digit application number (fill in with zero(s) if number contains less than 7 digits) For US application numbers, add the two-digit series code* after the dash: YYYYUS-SCNNNNNN	1999EP-0202618 /AP 1989WO-US01469 /AP 1994US-08352062 /AP 2013US-13974634/AP
- Country		• The application country using the two-letter ISO country code	EP /AP
- Date		• The application date in the format: YYYYMMDD YYYYMM YYYY Do not use numeric operators.	1999-08-12 /AP 1999-08 /AP 1999 /AP
Application Date: - All application dates - Earliest application date	/APD /EAPD	Search in the format: YYYY-MM-DD YYYY-MM YYYY Use numeric operators: =, <, >, <=, >=	APD=1999-08-12 APD=1999-06:1999-10 APD>=1992 EAPD=2011-10-03 EAPD>=2011 EAPD<=2011-10
First application country for the family	/EAPC	Search by country codes.	FR /EAPC (JP OR CN OR TW) /EAPC
Original PCT application number Provides the original PCT filing number for member patent office documents filed via the PCT	/PAP	Search using: - Presence of the field - The number in the format: YYYYWO-CCNNNNN - The application date with the PAPD subfield and numeric operators	PAP=YES 2002WO-CU00011 /PAP PAPD/PAP=2002-11
Filing Details	/FD	This field is available for US records and provides information such as whether one patent is based upon another (continuation of, CIP, division of). Search using: - Presence of the field - Standardized Questel format YYYYCC-NNNNNNN - Date using the FDD subfield and numeric operators	FD=YES 1995US-60000189 /FD FDD/FD=2010
* For a list of US Series Codes: www.uspto.gov/web/offices/ac/ido/oeip/taf/filingyr.htm			

Priority Data

Search by	Index	Search Hints	Examples
Family Priority Data: - Number - Country - Date	/PR	Search using: • The priority number in the format: YYYYCC-NNNNNNN YYYY = 4-digit application year CC = ISO country code NNNNNNN = 7 digit application number (fill in with zero(s) if number contains less than 7 digits) For US application numbers, add the two-digit series code* after the dash: YYYYUS-SCNNNNNN • The priority country using the two-letter ISO country code • The priority date in the format: YYYYMMDD YYYYMM YYYY Do not use numeric operators.	 1986NL-0003303 /PR 2001WO-US06520 /PR 2007US-11962576/PR US /PR 1998-08-12 /PR 1998-08 /PR 1998 /PR
Priority Date: - All priority dates - Earliest priority date	 /PRD /EPRD	Search in the format: YYYY-MM-DD YYYY-MM YYYY Use numeric operators: =, <, >, <=, >=	 PRD=1998-08-12 PRD=1998-04:1998-08 EPRD>=1997
First priority country in the family	/EPRC	Search by country codes.	FR /EPRC (JP OR CN ORTW) /EPRC
Number of priorities	/NPR	Use numeric operators: =, >, <, >=, <=.	NPR=3 NPR>1
* For a list of US Series Ccodes: www.uspto.gov/web/offices/ac/ido/oeip/taf/filingyr.htm			

Cross-file Searching with Numbers

Search by	Index	Search Hints	Examples
Standardized Numbers: - Priority - Application - Publication	 /XPR /XAP /XPN	To facilitate searching across patent databases, Questel has created a standardized format for the 3 kinds of number: priority, application and publication. They can be extracted with the MEM command, then searched with the *MEM super-term.	MEM /XPN *MEM /XPR

International Patent Classification

Search by	Index	Search Hints	Examples
International Patent Classification codes	/IPC	The /IPC index simultaneous searches the following fields: • ICH: Codes as they have been assigned by national offices at each stage of publication The index /ICH can restrict the search to historical IPC codes. • IC: Updated Codes The index /IC allows you to restrict the search to updated IPC codes. Search with one of the following formats: - full index: ANNA-NNN/NN - group*: ANNA-NNN - subclass*: ANNA - class: ANN #: use the # symbol. * These two formats are searchable without truncation.	G10L-015/26 /IPC G10L-015 /IPC G10L /IPC G10# /IPC
	/ICM	The index /ICM allows you to restrict the search to the main code of each member.	H01M-008 /ICM
	/FMIC	The index /FMIC allows you to restrict the search to the main family code (associated with the latest family member publication).	H01M-008 /FMIC

Cooperative Patent Classification

Search by	Index	Search Hints	Examples
Cooperative Patent Classification codes CPC is used in place of ECLA and ICO since 1 January 2013.	/CPC	The /CPC index simultaneous searches the following fields: • CPCH: Codes as they were granted by the EPO and the USPTO at each stage of publication The index /CPCH can restrict the search to historical CPC codes. • CPC: Updated Codes Search by: - Full code (conversion of ECLA and mirrored ICO codes) ANNA-NNN/NN ANNA-NNN/NN/NNN ANNA-NNN/NNN/NN (2-3 digits after the first slash, 1-3 digits after second the slash - Entering the second slash is optional). - Full code (conversion of orthogonal ICO codes) ANNA-2NNN/NNNNN (2-5 digits after the slash) - Group*: ANNA-NNN or ANNA-2NNN - Subclass*: ANNA - Class: ANN#; use the # mask. * These two formats are searchable without truncation.	G06K-019/02 /CPC G06K-019/02/7 /CPC G06K-019/06/065 /CPC G06K-019/077/43 /CPC G06K-019/06065 /CPC A01D-2017/108 /CPC H01L-2021/60292 /CPC G06K-019 /CPC A10D-2017 /CPC G10K /CPC G10# /CPC
	/CPCM	The index /CPCM allows you to restrict the search to the main code of each member.	A01D-2017/108 /CPCM
	/FCPC	The index /FCPC allows you to restrict the search to the main family code (associated with the latest family member publication).	A01D-2017/108 /FCPC
Concordance between the old ECLA and ICO codes and new CPC codes is available on the EPO website: www.cooperativepatentclassification.org/cpcConcordances.html			

Former European Classifications

Search by	Index	Search Hints	Examples
ECLA and In Computer Only Classifications Used by EPO examiners until 2012 - Replaced by CPC	/EC	Search by: - Full index: ANNA-NNN/NNN ANNA-NNN/NNA ANNA-NNN/NNAN ANNA-NNN/NNANA ANNA-NNN/NNANAN - Group*: ANNA-NNN - Subclass*: ANNA - Class: ANN#; use the # mask. * These two formats are searchable without truncation. ICO is derived from ECLA and where the letters A, B, C, D, E, F, G and H are replaced by the letters K, L, M, N, P, R, S and T. Was used for: - Describe the characteristics for which there is also an ECLA code and classifies additional information (mirrored codes) - Describe the characteristics for which there is no ECLA code (orthogonal codes) - Classify information according to different criteria compared to ECLA (additional subdivisions ECLA) ICO - two classes were created to cover nanotechnology (Y01) and sustainable energy technologies (Y02).	 C21D-001/773 /EC C21D-006/00K /EC B25G-001/06S1 /EC G10L-015/06A3S /EC C12Q-001/68D2E1 /EC G10L-015 /EC G10L /EC G10# /EC S10L-015/18C1 /EC M08L-009/06 /EC M08L-009 /EC M08L /EC M08# /EC

United States Classification

Search by	Index	Search Hints	Examples
US Classification codes: - Historical codes - Updated codes	 /PCLH /PCL	Available for US documents only. The US classification code (9 or 12 characters) is formatted as: MMMSSSDDDAAA MMM = 3-digit class SSS = 3 digit subclass or DIG for "Digest" DDD = 3 digits AAA = 1-3 optional alphanumeric characters Search by : - Class - Subclass or Digest including mention DIG - Full code For a comprehensive search, use both fields simultaneously.	 379 /PCL 379093 /PCL 210DIG017 /PCL 379093150 /PCL 379093150 /PCL/PCLH
	/PCLM	The /PCLM index allows you to restrict the search to the main classification of each US member.	343754 /PCLM

Japanese Classification

Search by	Index	Search Hints	Examples
FI and F-terms Available for 97% of JP documents		Classification derived from the 6th edition of the IPC and used by JPO examiners for Japanese documents.	
- FI (File Index) Contains no additional zeros or dashes (unlike Questel format for IPCs)	/FI	The FI may be made of: - An IPC code in the format : ANNA[N]N/NN[N] - An IPC code followed by a symbol (1 letter) in the format: ANNA[N]N/NN[N] A - An IPC code followed by a subdivision (3 digits) in the format: ANNA[N]N/NN[N]NNN - An IPC code followed by a subdivision and a file symbol in the format: ANNA[N]N/NN[N]NNNA - An IPC code with a "facet" (3 letters)	 A01B1/16 /FI G10L9/20A /FI G11B11/105506 /FI G11B11/105506A /FI G11B11/08ZNM /FI
- F-term (File Forming Term)	/FTM	All technical areas covered by FIs are defined themes and some of these themes are divided into F-terms. Search by: - Theme in format NANNNNANNN - Theme and point of view in format NANNNAA+ - Full F-term in format NANNNAANN or NANNNAANN.N	 4C206 /FTM 4C206CB+ /FTM 4C206CB23 /FTM 4J002AC03.3 /FTM
Code definition is available on this website www5.j-platpat.inpit.go.jp/pms/tokujitsu/pmgs_en/PMGS_EN_GM101_Top.action			

Inventor

Search by	Index	Search Hints	Examples
Name of the inventor:			
- At each stage of publication	/INH	The /INH index searches the name of the inventor for all stages of publication.	
- At the most recent publication stage	/IN	The index /IN restricts the search to the inventor at the most recent publication stage. For CN, JP, KR, RU, TH and TW publications, the INH and IN fields an English Machine translation is provided, it is then automatically replaced by the official data when it becomes available. Search by single terms (operators) or phrases (implied adjacency), using truncation Use the D or S operator to combine full name (first and surname in full, because the two entries co-exist). For a comprehensive search, use both fields simultaneously. With the IND and MEMS commands, use the /INN index.	(KAO D (YO W HONG)) /INH (KAO YO HONG) /INH (PUYPLAT S (O OR OLIVIER)) /INH SMITH /IN/INH IND /INN CURTIS
- In non-Latin original language	/OIN	Search by the name of the inventor in non-Latin original language for CN, JP, KR, TW, RU/SU publications and for PCT applications published in Russian, Korean, Japanese and Chinese.	
Inventor Address: - Country - US State*	/INAD	Search by: - ISO 2-letter country code using the COUNTRY subfield. - ISO 2-letter US State code using the STATE subfield*. *Available for US documents only.	 COUNTRY/INAD=US STATE/INAD=ME
* For a list of US State Codes: about.usps.com/who-we-are/postal-history/state-abbreviations.htm			

Applicant or Assignee

Search by	Index	Search Hints	Examples
Name of the applicant or assignee:			
- At each stage of publication	/PAH	The /PAH index searches the name of the applicant or assignee for all stages of the publication in the EPO format.	
- At the most recent publication stage	/PA	The PA field contains the standardized assignee name (see NPA). If this is not available, contains the name at the most recent publication stage.	
		For CN, JP, KR, RU, TH and TW publications, an English Machine translation is provided, it is then automatically replaced by the official data when it becomes available.	
		Search by single terms (operators) or phrases (implied adjacency), using truncation For a comprehensive search, use both fields simultaneously.	(TEXAS W INSTRUMENT?) /PA (KIMBERLY CLARK) /PA/PAH
		With the IND, MEM and MEMS commands, use the /PAN index. Note: Crossfile searching (MEM) and statistical analysis (MEMS) are performed on the names only for the last publication stage.	IND /PAN MAX PLANCK
- In non-Latin original language	/OPA	Search by the name of the applicant in non-Latin original language for CN, JP, KR, TW, RU/SU publications and for PCT applications published in Russian, Korean, Japanese and Chinese.	
Standardized patent assignee name of each member	/NPA	This field provides the name of company standardized by Questel. This standardization includes corrections of typographical errors, the removal of non-meaningful parts of the name such as legal forms (INC, SA, GMbH, LTD, etc.) and removing spaces and periods in acronyms. The field will supply, if possible, the latest name of the company. Names are deduped when they are exactly identical for different members.	
		Search by single terms using search operators and truncation or full name using implied adjacency	PANASONIC /NPA
		With the IND, MEM and MEMS commands, use the /NPAN index.	MEMS SET /NPAN

Applicant or Assignee (cont'd)

Search by	Index	Search Hints	Examples
Standardized patent assignee name of the family	/FPA	This field extracts the « best » name(s) for the family from the NPA field. The extraction is based on the most recent member. For families which contain several members, names coming from machine translation and from JP publications are excluded of the selection. Search by single terms using operators and truncation or full name using implied adjacency. With the IND, MEM and MEMS commands, use the /FPAN index.	GEMALTO /FPA
US Reassignments Available for US documents only (USPTO source)	/REAS	Search by: - Presence of field - Single words (operators) or phrases (implied adjacency)	REAS=YES PANASONIC /REAS PANASONIC /REAS AND HITACHI/PA
Assignee Address: - Country - US State* - City - Post code	/PAAD	Search by: - ISO 2-letter country code using the COUNTRY subfield - ISO 2-letter US state code using the STATE* subfield Available for US documents only - City name using the CITY subfield and the PAAD field For names containing an hyphen, use limited truncation ?. - Full or truncated post code using the POSTCODE subfield and the PAAD field To combine several subfields, use the SDOC operator.	COUNTRY/PAAD=JP STATE/PAAD=CO CITY/PAAD=LYON OR LYON/PAAD (CITY/PAAD=CLERMONT?FERRAND) OR (CLERMONT W FERRAND)/PAAD (POSTCODE/PAAD=67+ OR POSTCODE/PAAD=68+) OR (67### OR 68###)/PAAD ((POSTCODE/PAAD=67+ OR POSTCODE/PAAD=68+) OR (67### OR 68###)/PAAD) SDOC COUNTRY/PAAD=FR
* For a list of US State Codes: about.usps.com/who-we-are/postal-history/state-abbreviations.htm			

Names Super-Index

Search by	Index	Search Hints	Exemples
Inventor + Assignee	/NA	This field allows for simultaneous searching of the Inventor and Assignee fields: IN, PA.	GUTMANN /NA

Representative

Search by	Index	Search Hints	Examples
Representative name	/RP	Information available for: US since 1971 EP since 1978 WO since 1978 FR since 1966 Search by single terms (operators) or phrases (implied adjacency), using truncation. For names of people, use the D or S operators to combine first name and surname. With the IND, MEM and MEMS commands, use the /RPN index.	GUIU /RP (ERNEST S GUTMANN) /RP IND /RPN REGI
	/ORP	The /ORP index allows to search by the name of the representative in non Latin original language for JP, CN, KR, TH and WO publications.	
Representative country	/RPAD	Available for US, EP and WO documents Search by 2-letter country code using the COUNTRY subfield.	COUNTRY/RPAD=FR

Other Names

Search by	Index	Search Hints	Examples
Licensee Available for US documents only (USPTO source)	/LIC	Search by : - Presence of field - Licensee name using single words (operators) or phrases (implied adjacency) - License year using keywords FROM for the beginning of the license and TO for the effective end of the license - License type using the LT subfield and keywords CONFIRMATORY for government licenses and LICENSE for the other licenses	LIC=YES APPLE /LIC (FROM 2007) /LIC (TO 2016) /LIC LT/LIC=CONFIRMATORY LT/LIC=LICENSE
Security interest Available for US documents only (USPTO source)	/SEC	Search by: - Presence of field - Name of the financial organization using single words (operators) or phrases (implied adjacency) - Pledge year using keywords FROM for the beginning of the license and TO for the effective end of the pledge	SEC=YES (BARCLAYS BANK) /SEC (FROM 2012) /SEC (TO 2014) /SEC

Citations

Citations (patent and non patent literature references) are available for the following publications:

AP – from 1984	EA – from 1996	LU – from 1999
AT – from 1983	EP – from 1978	MY – 2003-2010
AU – from 1978	ES – from 1993	NL – from 1965
BE – from 1988	FR – from 1969	NO – from 2009
BG – from 1999	GB – from 1983	RU – from 2005
CH – from 1982	GR – from 1988	SG – from 2001
CN – from 1987	HR – from 2005	TR – from 1987
CZ – from 1997	IT – from 2010	TW – from 2006
DE – from 1943	JP – from 1972	US – from 1947
DK – from 1956	KR – from 2000	WO – from 1978

Patents cited in search reports are displayed in the CT field under the title « Search Report » or « Examiner citations » for all the countries listed above.

- For US, EP, WO, FR, DE, NL, BE, GR, CH, GB, TR, LU and DK publications, this field also contains Applicant citations.
- For EP publications, this field also contains Opposition citations and Observer Citations (art. 115).
- For JP publications, citations are listed in 4 categories: Opposition citations (reason for opposition), Opposition citations (reason for decision), Examiner citations (reason for refusal) and Citations in registration report.

Search is detailed on next page: /CTN index for searching for cited patents and /CTGN index for searching for citing patents.

Cited non patent literature is available for all the countries listed above except BG.
References to cited non patent literature are displayed in the REF field under the title « Search report references » or « Examiner references ».

- For US, EP, WO, FR, DE, NL, BE, GR, CH, GB, TR, LU and DK publications, the REF field also contains applicant literature references.
- For EP publications, the REF field also contains Opposition references and Observer references (art. 115).

Search by	Index	Search Hints	Examples
Non patent literature Citations	/REF	Search using single words (operators) or phrases (implied adjacency), using truncation on: - Title - Authors - Source - XP number assigned by the EPO examiners - Presence of field	(RECOGNITION W SYSTEM?) /REF DESHMUKH /REF (SIGNAL 1W MAGAZINE) /REF XP002058560 /REF REF=YES

Citations (cont'd)

Search by	Index	Search Hints	Examples
CITED PATENTS CITING PATENTS	/CTN /CTGN	Search by presence of the CTN field to retrieve families with cited patents, by presence of the CTGN field to retrieve families with citing patents.	CTN=YES CTGN=YES
- Publication number		Search by standardized patent number in the format CCNNNNNNN (same as the PN field). Fill with hyphens if needed.	EP-248377 /CTN USD308968 /CTGN
- Publication country		Search by two-letter country code	EP /CTN US /CTGN
- Citation author		Search by keywords below using the WHO subfield: - Applicant - Examiner - Third_Party - Unknown	 WHO/CTN=APPLICANT WHO/CTN=EXAMINER
- Self citation		Search by Keyword Y (for yes) or N (for no) using the SELF subfield.	SELF/CTN=Y SELF/CTN=N
- Relevancy category		Relevancy category codes, also known as relevance indicators, are used by the EPO in their search reports. They are found in EP, FR and PCT search reports. I - Particularly relevant when taken alone affecting the inventive action X - Particularly relevant if taken alone and affecting novelty * Y - Particularly relevant if combined with another document in the same family A - Technology background O - Unwritten disclosure P - Intermediate document T - Theory or principle underlying the invention E - Earlier patent document, but published on, or after, the filing date D - Document cited in the application L - Document cited for other reasons * Before the creation of the I code, the definition of the X code was: Particularly relevant if taken alone Search by relevancy codes above using the CAT subfield.	CAT/CTN=X CAT/CTN=X OR CAT/CTN=Y
Standardized cited patent number The CITB and CITF commands work on the /XCT field.	/XCT	To facilitate cross file searching with other patent databases, Questel has created a standardized cited number field. Numbers can be extracted with the MEM command, then searched with the *MEM super-term.	MEM /XCT *MEM /XPN

Legal Status

Search by	Index	Search Hints	Examples
Free text on events	/ACT	Search in English or in the application language by using single words or phases, and truncation. Note: Left-hand truncation is not authorized. As ACT is structured in subfields, it allows precise searches. See hereafter for searching in subfields.	(SEARCH REPORT) /ACT ((NON PAYMENT) OR (FAILURE 1W PAY))/ACT
Data calculated by Questel:			
State	STATE	Search with the keywords: - ALIVE - DEAD* Use the numeric operator =.	STATE/ACT=ALIVE STATE/ACT=DEAD
Status	STATUS	Search with the keywords: - PENDING - GRANTED - EXPIRED - LAPSED* - REVOKED Use the numeric operator =. * Pending applications for which there is no activity for several years are declared "Pending Application Likely abandoned" and therefore LAPSED / DEAD.	STATUS/ACT=GRANTED STATUS/ACT=LAPSED STATUS/ACT=PENDING OR STATUS/ACT=GRANTED
Actual or expected expiry date	EED	Search with the date format: YYYY-MM-DD YYYY-MM YYYY Use numeric operators: =, <, >, <=, >=.	EED/ACT=2020-15-03 EED/ACT>=2010-11 EED/ACT<=2015
STATE, STATUS and EED subfields are also provided for countries not covered by the EPO PRS database.			
Date of event publication / communication	AD	Search with the date format: YYYY-MM-DD YYYY-MM YYYY Use numeric operators: =, <, >, <=, >=.	AD/ACT=2010-06-16
Actual date of the event	EFFD		EFFD/ACT>=2010-06
Event code**	CO	Search in the format CC/NNNN. CO = Country code NNNN = 2 to 4 character alphanumeric code Use the numeric operator =.	CO/ACT=US/FP CO/ACT=EP/PGFP

** The list of event codes is available on the EPO website:
http://documents.epo.org/projects/babylon/rawdata.nsf/0/3A4EE91865872B7DC12577DC00562F8F/$File/le-codes-en1046.txt

Legal Status (cont'd)

Search by	Index	Search Hints	Examples
Index assigned to the event	SI	This index specifies if the event is positive or negative. - POS (positive) - NEG (negative) Use the numeric operator =.	 SI/ACT=POS SI/ACT=NEG
Event groups	EG	To facilitate researching actions, Questel created 16 event codes that bring together similar actions of different patent authorities: ADM Administrative notifications CCL Classification amendments COR Corrections, amendments DCS Designated states ENP Entry into national phase, translations (AP, EA, EP, OA, WO) EXM Requests for examination, review procedures and review process, research reports LIC Licensing and operating agreement NENP Non-entry into national phase NIF Not in force, disqualifications, expiration, refusal, recalls NMC Name change of applicant, assignee, inventors; other: opponents, applicants NOPP No opposition to registration OPP Opposition, re-examination PIF Payment of annuities, in effect, registered, issued RAS Reassigned RES Restitution, restoration: in effect SPC Actions concerning complementary or supplementary certificates of protection, extension of protection period. Search with a code and the numeric operator =.	 EG/ACT=LIC EG/ACT=RAS EG/ACT=SPC EG/ACT=RES OR EG/ACT=SPC
<u>Countries affected by the event</u>: - Application country - Publication country - Designated countries	 APC PC CC	Search with country code and the numeric operator =. These subfields are useful in combination with other queries to restrict the search to a particular member of a family. Use the P (paragraph) operator to connect the search criteria.	PC/ACT=EP CC/ACT=FR (PC/ACT=FR OR CC/ACT=FR) P EG/ACT=SPC (PC/ACT=US OR CC/ACT=US) P STATUS/ACT=GRANTED

Legal Status (cont'd)

Search by	Index	Search Hints	Examples
Dates affected by the event:			
- Application date	APD	Search with the date format : YYYY-MM-DD	APD/ACT>=2005-12
- Publication date	PD	YYYY-MM YYYY	PD/ACT<=1990
- Application date in countries designated by a WO or an EP	CAPD	Use numeric operators : =, <, >, <=, >=.	CAPD/ACT<=1995-05
- Date of publication in the country designated by a WO or an EP	CPD		CPD/ACT=2008-07-04
Numbers affected by the event:			
- Publication number	PN	Search using the Questel standardized number.	PN/ACT=EP1131715
- Stage of publication code	KD	Searching using the 1 or 2 character code.	KD/ACT=B1 PC/ACT=EP P KD/ACT=B1
- Application number in countries designated by a WO or an EP	CAP	Search using the Questel standardized number.	CAP/ACT=2001US-10629694
- Publication number in countries designated by a WO or an EP	CPN	Search using the Questel standardized number.	CPN/ACT=EP1414368
- Stage of publication code in the country designated by a WO or an EP	CKD	Searching using the 1 or 2 character code.	CC/ACT=EP P CKD/ACT=A1
Other subfields of the /ACT index:			
Expiry date (essentially GB documents designated by an EP)	EXD	Search with the date format : YYYY-MM-DD	EXD/ACT>=2001
Extension date (for some RU, EP and US)	EXTD	YYYY-MM YYYY	EXTD/ACT>2005
Withdrawal date (EP)	WTHD	Use numeric operators: =, <, >, <=, >=.	WTHD/ACT>=1990
Date of maintenance fee payment (for countries designated by an EP)	PAY		PAY/ACT=2011-02
Year number (1 to 20) of payment (US, EP)	YR	Use numeric operators: =, <, >, <=, >=.	YR/ACT=20 YR/ACT>=3
Number of extension days (US)	XDAY		XDAY/ACT>=300

Legal Status (cont'd)

Search by	Index	Search Hints	Examples
Owner(s) – original and current Essentially available for some US, EP, BE, DE documents	/OWR	The field is present when there have been changes in ownership. Search by single words (operators) or phrases (implied adjacency). Truncation may be used. Addresses are not systematically included. With the IND, MEM and MEMS commands, use the /OWRN index.	(QUADRANT DRUG DELIVERY) /OWR ((INT+ W BUS+ W MAC+) OR IBM) /OWR
Inventor(s) Available for EP & DE documents	/INV	The field is usually present when there have been changes or corrections to an inventor's name or address. It contains the surname, first name, city and country code of the inventors. Search by single words connected with the S operator, or by phrases (implied adjacency). Truncation may be used. With the IND, MEM and MEMS commands, use the /INVN index.	((PEREIRA S ALEXANDRE) AND FR) /INV
Representative Essentially available for EP, DE, CH documents	/REP	The field is present when there have been changes to the representative. Search by single words (operators) or by phrases (implied adjacency) on the representative name. Truncation may be used. With the IND, MEM and MEMS commands, use the /REPN index.	(ISLER AND PEDRAZZINI) /REP
Opponent Essentially available for EP documents	/OPP	Search by single words (operators) or by phrases (implied adjacency) on the opponent name. Truncation may be used. With the IND, MEM and MEMS commands, use the /OPPN index.	GEROLYMATOS /OPP
Requestor Essentially available for CN, EP, AU, FR, NZ documents	/REQ	The field is present when there are: licenses, SPC, mortgages, cancellation of financial interests. Search by single words (operators) or by phrases (implied adjacency) on the requestor name. Truncation may be used. With the IND, MEM and MEMS commands, use the /REQN index.	(HSBC BANK) /REQ
All the names	/NAM	The /NAM Super Index simultaneously searches the OWR, INV, REP, OPP and REQ fields.	((INT+ W BUS+ W MAC+) OR IBM) /NAM

Other Indexes

Search by	Index	Search Hints	Examples
Designated states for European Patents (EP) and PCT applications (WO)	/DS	Search by ISO country code using the two letter format CC. The EP designated states are from the last EP publication stage.	AT /DS (FR OR GB) /DS
Publication language	/LA	Language is provided for EP and WO documents and in all other cases where the language is not the sole official language of the country In order to display the list of languages, use the IND command. Search using the English name of the language or using the 3 first letters of this name.	IND /LA ENGLISH /LA ENG /LA
Notes (US, EP, WO)	/NO	For US documents, /NO allows to search by USPTO examiner names and company representative names. For EP and WO documents, NO contains information on divisions, changes or corrections. Search by single words or phrases, or by presence of the field.	(BARKAI D RAPHAEL) /NO NO=YES
Number of figures, claims, etc (US, JP, KR)	/NUM	Search for : - Number of drawing pages – NDR (US) - Number of figures – NFG (US, JP) - Number of claims – NCL (US, JP, KR) - Number of independent claims – ICL (US*) - Number of exemplary claims – ECL (US*) - Art Unit – ART (US*) - Number of pages – NPS (US*) - Days of extension – EXTD (US*) - Term of patent – TRM (US*) Use numeric operators : =, >, <, >=, <= * Granted patents only	NDR>=20 NFG<=50 NCL=10:15 ICL=4 ECL=1 ART=271 NPS=10:50 EXTD=134 TRM=14

Other Indexes (cont'd)

Search by	Index	Search Hints	Examples
Case ID number - US documents (MAXVAL source)	/CID	This field is present for litigation filed in the 94 US District courts, from 1980 forward. Access to the litigation content is available with a subscription.	CID=YES
License ID number - US documents (KTMINE source)	/LID	This field is present for US documents which have a license agreement. Access to the license content is available with a subscription.	LID=YES
Family accession number in FamPat	/FAN	Sequential number assigned to a FamPat family	66142304 /FAN
Member accession number in PlusPat and FamPat	/APID	Sequential number assigned to the document in the PlusPat record and which is kept by each member in the FamPat family Unlike the FAN and XPN numbers which may change following a family recomposition or a numbering modification, the APID is a unique number which is permanently assigned to the members.	107523059 /APID
Accession number of the legal status record in LGST	/LAN	Number containing application number assigned to the Legal Status record in FamPat and LGST databases	EP09010508A /LAN

Update Codes

<table>
<tr><th>Search by</th><th>Index</th><th>Search Hints</th><th>Examples</th></tr>
<tr><td>New families in the database:
- Weekly
- Monthly</td><td>
/UP
/UP4</td><td rowspan="3">

Use the relevant update index and search the code in the following format:

YYYY-WW (week)
YYYY-MM (month)
YYYY+ (year)</td><td>

2014-23 /UP
2014-06 /UP4</td></tr>
<tr><td>• Addition of equivalents or changes to publication stage:
- Weekly
- Monthly

• Addition of citations (weekly)</td><td>
/UE
/UE4

/UCT</td><td>

2014-23 /UE
2014-06 /UE4

2014-23 /UCT</td></tr>
<tr><td>• Addition of Human produced English Abstracts 1st time:
- Weekly
- Monthly

• Addition of Machine or Human produced English Abstract 1st time:
- Weekly
- Monthly

• Addition of any Human language abstract 1st time:
- Weekly
- Monthly</td><td>

/UAB
/UAB4

/UMTA
/UMT4

/UABA
/UAA4</td><td>

2014-23 /UAB
2014-06 /UAB4

2014-23 /UMTA
2014-06 /UMT4

2014-23 /UABA
2014-06 /UAA4</td></tr>
<tr><td>Addition of CPC codes for the 1st time, or modifications to CPC codes</td><td>/UEC</td><td>Search the code in the following format:
YYYY-WW (week)
YYYY+ (year)</td><td>

2014-23 /UEC
2014+ /UEC</td></tr>
<tr><td>Entry of new families in the database + Changes to families already in the database:

- Weekly
- Monthly</td><td>

/QW
/QM</td><td>Includes:
- New families entered into the database except the documents published before 2006 and documents with D0 kind code
- Modified families by the addition of one or more of the following six fields: ETI, EAB, PA, CPC, FI, FTM

Use the relevant update index and search the code in the following format:
YYYY-WW (week)
YYYY-MM (month)
YYYY+ (year)</td><td>

2014-23 /QW
2014-06 /QW
2014+ /QW</td></tr>
<tr><td colspan="4">All the update codes above are available for use in SDI profiles.</td></tr>
</table>

Update Codes (cont'd)

Search by	Index	Search Hints	Examples
Entry or update week of events (ACT)	/EUP	Use the relevant update index and search the code in the following format: YYYY-WW (week	2013+ /EUP 2013-47 /EUP
Entry or update week of any legal status information	/LUP LGUP*		2012-09 /LUP 2012+ /LGUP
Entry or update month of any legal status information	/LUP4	Search the code in the following format: YYYY-MM (month)	2012-02 /LUP4
All codes above are available for legal status alerts. *** Only this update code is available for use in SDI profiles.**			

Document Display

■ Classical Formats

Fields	Formats													
	ABST	ALL (3)	BIB	BRF	DOC	DOCF	FUF	PAGE	MAX (or FULL, FU)	PDFR	SCAN (or SC)	STDR (default)	TAB	TEST (or TR)
AB (1)	✓	✓			✓			✓	✓	✓			✓	
ADB		✓							✓				✓	
AP	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓		✓	✓	
CPC		✓		✓			✓	✓	✓	✓		✓	✓	✓
CT	✓	✓	✓				✓	✓	✓					
DESC		✓												
DS		✓		✓	✓	✓	✓	✓	✓	✓		✓		
EC		✓		✓			✓	✓	✓	✓		✓	✓	✓
ECLM (2)		✓												
FAB						✓	✓							
FAN	✓	✓	✓	✓				✓	✓		✓	✓	✓	✓
FD	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓		✓		
FI		✓		✓			✓	✓	✓	✓		✓	✓	✓
FTM		✓		✓			✓	✓	✓	✓		✓	✓	✓
IC		✓		✓			✓	✓	✓	✓		✓	✓	✓
ICLM		✓							✓				✓	
IN	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓		✓	✓	
INH	✓	✓	✓	✓	✓	✓	✓	✓	✓			✓		
IT					✓	✓	✓							
LA							✓							
MED	✓	✓			✓	✓	✓	✓	✓				✓	
NO	✓	✓					✓	✓	✓			✓	✓	
OBJ		✓							✓				✓	
OTI					✓	✓	✓							
PA	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓		✓	✓	
PAH	✓	✓	✓	✓	✓	✓	✓	✓	✓			✓	✓	
PAP	✓	✓			✓	✓	✓	✓	✓	✓		✓		
PCL		✓		✓			✓	✓	✓	✓		✓	✓	✓
PN	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓		✓	✓	
PPN	✓	✓			✓	✓	✓	✓	✓	✓		✓		
PR	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓		✓	✓	
REAS	✓	✓	✓	✓	✓	✓	✓	✓	✓			✓	✓	
REF	✓	✓					✓	✓	✓					
RPH	✓	✓	✓	✓	✓	✓	✓	✓	✓			✓	✓	
TI (1)	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓	✓
UP	✓	✓					✓	✓	✓			✓	✓	

The APD, PD and PRD fields are included respectively in the AP, PN and PR fields.
(1) TI and AB fieds display the title and the abstract in the preferred language. To set the preferred language, see the DOCLA option on next page.
(2) When the ECLM field is not present, then the FCLM field (or default GCLM or OCLM fields) is displayed.
(3) Unlike the other formats, the ALL format includes information for all family members, only the claims and description are from the representative member.

FIELD CONTENT

PN and AP fields: Publication and application dates apply to all members, all stages of publication and are by default sorted in ascending chronological order.
The order can be modified with the user option **PSORT**.
(P)**OP PSORT LAST** For a descending chronological order
(P)**OP PSORT FIRST** To return to the ascending chronological order

TI, OTI, IT, AB, OBJ, ADB, ICLM, ECLM and DESC fields: The content will be extracted from a single publication for the family, based on information listed in the user options (except in the ALL format).

● **DOCLA** option: By default, the option is set to the English language (DOCLA EN) if the search language preference is set to English (LA 2) and to the French language (DOCLA FR) if the search language preference is set to French (LA 1).
The DOCLA option allows to modify the preferred language for the title, abstract, claims and description.
Example: (P)**OP DOCLA DE** To display data in German
You can specify up to 3 languages.
Example: (P)**OP DOCLA DE EN** To display data in German. If German is not available, data will be displayed in English.

To disable DOCLA option: (P)**OP DOCLA OFF**
When DOCLA is disabled: If the English title (ETI) is not available, the content of the FTI field (or GTI or OTI) will be displayed in the TI field. If the English abstract (EAB) is not available, the content of the FAB field (or GAB or OAB) will be displayed in the AB field. If English claims are not available, the ECLM field will be replaced by FCLM or GCLM or OCLM. The member selection is managed by the MFAM option.

● **MFAM** option: Allow to set a list of preferred countries (up to 7). If no selection is made, the default is set as the PCT minimum documentation collection with the order as follows: EP, US, WO, GB, FR, DE, CH, BE, JP, SU/RU. This means that title, and Abstract data will be selected from the EP record as a basis for building the record. If there is no EP record in the family, title, assignee, inventor and abstract data will be selected from the US record. If there is no US record in the family, data from the WO record will be used, and so on. For the AB, OBJ, ADB and ICLM fields, the content is retrieved from all family members when information is available in display formats ALL and TAB, regardless of the MFAM setting.

The order of priority for displays is DOCLA then MFAM. If the DOCLA option is disabled, the display is managed by MFAM only.

Two other user options are available:

● **FTSTG** option: By default, for EP and US documents, claims and description are displayed from the application The order can be modified to display granted patent claims and descriptions (when available).
(P)**OP FTSTG GRT** To view the description and claims of EP or US granted patents
(P)**OP FTSTG APP** To return to the display of claims and the description of the application

● **HITS** option: Allows to displays the title, abstract, claims and descriptions that contain the search terms, which may give a composite view of the family, such as the title of one member, the abstract of a second member and the claims and the description of a third member.
If the search terms appear in the same field of several family members, the display of the hits is based on the DOCLA and MFAM selections. By default, HITS is disabled.
(P)**OP HITS ON** To enable the option
(P)**OP HITS OFF** To re-disable the option

The FTSTG and HITS options are mutually exclusive. If the HITS option is enabled, the FTSTG option is ignored.

PA, PR, IC, CPC fields: The names of the assignee, the priority data and the IPC, CPC classification codes are extracted from all members at the last stage of publication and are deduped. They are sorted alphabetically for assignees and classification codes, in ascending chronological order for priority data.

■ L Formats

These formats will show the corresponding stage (STG), application data (AP) and filing details (FD) in the PN field after each publication number.

ABST	--------→ABSL	PAGE	--------→PAGL
ALL	--------→ALLL*	MAX (ou FU)	--------→MAXL (ou FUL)
BIB	--------→BIBL	PDFR	--------→PDFL
BRF	--------→BRFL	STDR	--------→STDL
DOC	--------→DOCL	TAB	--------→TABL

*.Unlike the ALL format, the ALLL format contains all claims fields (ECLM + FCLM + GCLM + OCLM) and the description field (DESC) from all members. It also includes the LIC and SEC fields.

The FAML format will display only the PN field with STG, AP and FD fields integrated. The APID field is added at the end of the record.

■ Format specific to Legal Status Information

Format	Fields
LEGL	FAN PN TI PA PAH REAS RPH IN INH AP PPN PAP FD PR DS LGL UP

■ DETAIL Option

The DETAIL option gives you the ability to display the record contents of each family member. The records are grouped by patent family to keep the context. The DETAIL option gives you the ability to drill down to see the details of each family member, including titles, abstracts, classifications, inventors, assignees, citations, key information, claims and description.

■ Image Display

To display the images in a family, use the IMG parameter.

Display of images: Add the IMG parameter to one field.
Example: **PRT FAN IMG**

Display of text and images: Add the IMG parameter to a format.
Example: **PRT MAXL IMG**

Images are displayed from one member in the priority order below:
US, EP, FR, WO, DE, JP, BR, IN, KR, RU, TW, CN, CA, GB

When all images are available for the member, they are all displayed if QWEB 3 is used.

Crossfile Display Features

In FamPat, you can display complementary information from other patent databases.

■ Legal Information from Another Database

Add one of these options to the display command:

LEGALEP	Displays legal data from EPPATENT
LEGALUS	Displays legal data from CRXX and LITA
LEGALIFI	Displays legal data from CRXX
LEGALERT	Displays legal data from LITA

Example: **PRT MAXL LEGALUS**

■ Field or Format from Another Database

Use the PLUS parameter to add a field or a format coming from another Patent database.

Syntax: PRT <FORMAT> PLUS <FIELD or FORMAT> (DATABASE)

Example: **PRT MAXL PLUS TI (DWPI)**

Caution: All these options may only be used in single file mode.

List of Fields

These fields may be used with the PRT, LI, BR, and =YES commands.

Biblio

AB*	Abstract in the preferred language
AP	Application data (numbers and dates) of the family
APD	Application dates of the family
APID	Member accession number in PlusPat and FamPat
CID	ID number of U.S. litigation
CPC	Cooperative Patent Classification codes – most recent publication stage
CPCH	Cooperative Patent Classification codes – at each publication stage
CPCM	Main code of the Cooperative Patent Classification for each member
CT	Cited patents
CTN	Standardized cited patents
CTGN	Standardized citing patents
DS	Designated countries
EAB	Original or machine translated English abstract
EAPC	Earliest application country in the family
EAPD	Earliest application date in the family
EC	European ECLA and ICO classification codes
EPD	Earliest publication date in the family
EPDG	Earliest grant date in the family
EPNC	Earliest publication country in the family
EPRC	Earliest priority country in the family
EPRD	Earliest priority date in the family
ETI	Original or machine translated English title – most recent publication stage
ETIH	English title – at each publication stage
FAB	Original French abstract
FAN	Family Access Number in the database
FCPC	Main code of the Cooperative Patent Classification in the family
FD	Filing details
FI	Japanese FI classification
FMIC	Main code of the International Patent Classification in the family
FPA	Standardized name of applicant or assignee of the family
FTI	Original French title – most recent publication stage
FTIH	French title – at each publication stage
FTM	Japanese F-term classification
GAB	Original German abstract
GTI	Original German title – most recent publication stage
GTIH	German title – at each publication stage
IC	International Patent Classification codes – most recent publication stage

* Do not use the =YES feature with the AB field.

Biblio (cont'd)

ICH	International Patent Classification codes – at each publication stage
ICM	Main code of the International Patent Classification for each member
IKD	Country codes and status
IN	Inventor(s') name(s) – most recent publication stage
INAD	Inventor(s') address(es) – country and US state
INH	Inventor(s') name(s) – at each publication stage
IT	English Index Terms for French publications
LA	Publication language
LIC	Licensee (US)
LID	ID number of US license
LPDG	Latest grant date in the family
MED	Name of the drug subject to French SPC
NO	Notes in US, EP and WO documents
NPA	Standardized name of applicant or assignee of each member
NPN	Number of published members in the family
NPR	Number of priorities in the family
NUM	Number of drawing pages, figures, claims, etc…
OAB	Original abstract in a language other than French, English or German
OIN	Inventor name in original non-latin language
OPA	Applicant name in original non-latin language
OPD	Other publication dates
ORP	Representative name in original non-latin language
OTI	Original title in a language other than French, English or German – most recent publication stage
OTIH	Original title in a language other than French, English or German – at each publication stage
PA	Assignee name at the most recent publication stage or standardized name
PAAD	Assignee address – Country, US State, City and Post code
PAH	Applicant name at each publication stage in the EPO format
PAP	PCT filing data
PCL	US classification codes – most recent publication stage
PCLH	US classification codes – at each publication stage
PCLM	Main US classification code of each US member
PD	All publication dates in the family (except OPD)
PDA	Publication date of application for each member
PDF	Date of first publication for each member
PDG	Publication date of grant for each member
PDL	Last publication date for each member
PN	Publication data (numbers, status and dates) of the family
PPN	Publication data of the original PCT application
PR	Priority data (numbers and dates) of the family
PRD	All priority dates in the family
QW et QM	Week or month of entry and modification of the family
REAS	US reassignment

Biblio (cont'd)

REF	Cited non-patent literature
RP	Representative name (for US, EP, WO and FR)
RPAD	Representative country
SEC	Security interest (US)
STG	Definition of kind codes
TECD	Technology domain
TI*	Title in the preferred language
UAB & UAB4	Addition of Human produced English Abstracts 1st time – week & month
UABA & UAA4	Addition of any Human language abstract 1st time – week & month
UCT	Addition of citations – week
UE & UE4	Addition of equivalents or changes to publication stage – week & month
UEC	Addition of CPC codes – week
UMTA & UMT4	Addition of Machine or Human produced English Abstract 1st time – week & month
UP &t UP4	Entry of new families in the database – week & month
XAP	Standardized application numbers
XCT	Standardized cited numbers
XPN	Standardized publication numbers
XPR	Standardized priority numbers

* Do not use the =YES feature with the TI field.

Key Content and Concepts

ADB	Advantages of the invention and drawbacks over prior art
ICLM	Independent claims
KEYW	Concepts
OBJ	Object of invention

Description and Claims

DESC	English description
DESX	Examples contained in the description of US documents
ECLM	English claims
FCLM	French claims
GCLM	German claims
OCLM	Claims in languages other than English, French or German
ODES	Description in languages other than English

Non-Latin characters contained in the OTI, OAB, OPA, OIN, ORP, OCLM and ODES fields are displayable only on QWEB 3 and Orbit.

Legal Status

ACT	Event text
AD	Date of event publication/communication
APC	Application country affected by the event
APD	Application date affected by the event
CAP	Application number in countries designated by a WO or an EP
CAPD	Date of application in countries designated by a WO or an EP
CC	Designated country affected by the event
CKD	Stage of publication code in the country designated by a WO or an EP
CO	Event code
CPD	Date of publication in the country designated by a WO or an EP
CPN	Publication number in countries designated by a WO or an EP
EED	Actual or expected expiry date
EFFD	Actual date of the event
EG	Event group
EXD	Expiry date
EXTD	Extension date
KD	Stage of publication code (kind code)
PAY	Date of maintenance fee payment
PC	Publication country affected by the event
PD	Publication date affected by the event
PN	Publication number affected by the event
SI	Index assigned to the event (positive or negative)
STATE	State (alive ou dead) of the members
STATUS	Status of the members
WTHD	Withdrawal date
XDAY	Number of extension days
YR	Year number of payment
EUP	Entry or update week of events (ACT)
INV	Inventor(s)
LUP, LGUP	Entry or update week of any legal status information
LUP4	Entry or update month of any legal status information
OPP	Opponent
OWR	Owner/Assignee
REP	Representative in case of change
REQ	Requestor

Extended Family Searching

■ Finding the Extended Family for a Number

To create an extended patent family for a particular invention, use the **FAM** command with the patent number (publication, application or priority). The XPN, XAP, and XPR fields may also be used for family searching as long as the Questel standardized format is used.

Syntax	**FAM CCNNNNNNN /PN**	(publication number)
	FAM AAAACC-NNNNNNN /AP	(application number)
	FAM AAAACC-NNNNNNN /PR	(priority number)

CC = ISO country code
AAAA = 4-digit year
NNNNNNN = number with 7 characters minimum

Examples	**FAM EP---1234 /PN**	standardized publication number
	FAM 1978EP-0100811 /AP	standardized application number
	FAM 1997DE-1020719 /PR	standardized priority number

■ Finding the Extended Families for a Set of Results

To create an extended patent family on a set of documents, use the **FAM** command followed by the search statement number. Family search is limited to 5000 documents in the results set

Syntax **FAM SS N**
N = Search Statement number

Example **FAM SS 5**
Performs a family search based on the results of the search statement n° 5

■ Displaying Extended Families

Extended family as multiple FamPat records

Use a dispaly L format, as for example the PAGL format.
List of L formats on page 47.

Extended family as a single record

This “virtual” record contains the following data:

- Publication, application and priority numbers and dates for all members
- Title, Assignee, and Inventor from the first member
- IPC codes from all members, PCL codes from all US members, FI and FTM codes from all JP members
- Abstract from the first member
- Citations from all members
- Designated states from EP and WO members

The first member which is displayed in the PN field is selected from the PCT minimum documentation collection in the order EP, US, WO, GB, FR, DE, CH, JP, SU/RU.
This means that title, assignee, inventor, and abstract data will be selected from the EP record as a basis for building the extended family. If there is no EP member in the family or if some data are missing for the EP document, these data will be selected from the US member. If there is no US member in the family or if some data are missing for the US document, these data from the WO member will be used, and so on
The publication numbers of the other members are alphabetically (country sorting) displayed in the next lines of the PN field.

A different patent country or authority may be selected as the basis for the building the merged record. Use the **MFAM** option which allows to specify a list of countries (1 to 7 country codes).
Example: **OP MFAM US**
In this example, the Title, Assignee, Inventor, and Abstract for the US member will be used for creating the records and the US numbers will appear first in the merged record. If there is not a US family member, then the default display will be used.

To display the extended family as a single record, use one of the formats below:

MTST or **MSC**	Displays titles from the FIRST member and ALL the classification codes
MMSS	Displays titles, assignee and inventor from the FIRST member and ALL the numbers, dates and designated states
MSTD	Displays titles, assignee and inventor from the FIRST member and ALL the numbers, dates, classification codes and designated states
MSTG	MSTD format with publication stages included in the PN field
MABS or **MSTA**	Displays titles, assignee, inventor and English abstract from the FIRST member and ALL the numbers, dates, classification codes and designated states
MSTE	MABS format restricting display of title to the English language
MINI	Displays English title, assignee and inventor from the FIRST member and ALL the numbers and dates
MASE	Displays English title, assignee, inventor and English abstract from the FIRST member and ALL the numbers and dates
MMAX	Displays titles, assignee, inventor and English abstract from the FIRST member and ALL the numbers, dates, classification codes, designated states and citations
MALL	Displays titles, assignee, inventor and abstract from the FIRST member and ALL the numbers, dates, classification codes, designated states and citations

Extended family as a single record supplemented with legal data

The **MFAMSTAT** command allows to a display the extended family as a single record in the MABS format, supplemented with legal data coming from the LGST database.
MFAMSTAT may also be used to display several extended families when the family searching is performed on a results set.

■ Displaying Extended Families (cont'd)

Extended family as a single record supplemented with citation report

After conducting an extended family search on a single patent family, you can display a complete citation report with the **FAMCITE** command.
The report displays in three parts:

- The original source family
- The citing patent families (families with a patent citing a member of the source family)
- • The cited patent families (families with a patent cited by a member of the source family)

The families are shown with the following fields:

- PN Publication number and date of all members
- ETI English title of the first member
- OTI Non-English title of the first member
- PA Assignee of the first member
- IN Inventor of the first member
- AP Application numbers and dates of all members
- PR Priority numbers and dates of all members
- CT Citations
- EAB English abstract of the first member

You can also display images by adding the IMG parameter. The command syntax is **FAMCITE IMG**.
LEGAL and FULLTEXT options cannot be used with FAMCITE.

List of Technology Domains

Below is the list of 35 technology domains which can be used with the /TECD index.

Analysis of Biological Materials
Audio-Visual Technology
Basic Communication Processes
Basic Materials Chemistry
Biotechnology
Chemical Engineering
Civil Engineering
Computer Technology
Control
Digital Communication
Electrical Machinery, Apparatus, Energy
Engines, Pumps, Turbines
Environmental Technology
Food Chemistry
Furniture, Games
Handling
IT Methods for Management
Machine Tools
Macromolecular Chemistry, Polymers
Materials, Metallurgy
Measurement
Mechanical Elements
Medical Technology
Micro-Structure and Nano-Technology
Optics
Organic Fine Chemistry
Other Consumer Goods
Other Special Machines
Pharmaceuticals
Semiconductors
Surface Technology, Coating
Telecommunications
Textile and Paper Machines
Thermal Processes and Apparatus
Transport